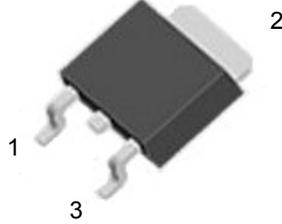
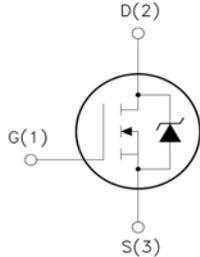


<p>CTKD50N06 60V N-Channel MOSFET</p> <p>Features:</p> <ul style="list-style-type: none"> <input type="checkbox"/> Low Intrinsic Capacitances. <input type="checkbox"/> Excellent Switching Characteristics. <input type="checkbox"/> Extended Safe Operating Area. <input type="checkbox"/> Unrivalled Gate Charge :Qg= 31nC (Typ.). <input type="checkbox"/> BVDSS=60V,I_D=50A <input type="checkbox"/> R_{DS(on)} : 0.018Ω (Max) @V_G=10V <input type="checkbox"/> 100% Avalanche Tested 	<p>TO-252</p>   <p>1.Gate (G) 2.Drain (D) 3.Source (S)</p>
--	--

Absolute Maximum Ratings (Ta=25°C unless otherwise noted)

Symbol	Parameter	Value	Unit
V _{DSS}	Drain-Source Voltage	60	V
I _D	Drain Current	T _C =25°C	A
		T _C =100°C	
V _{GS(TH)}	Gate Threshold Voltage	±25	V
E _{AS}	Single Pulse Avalanche Energy (note1)	360	mJ
I _{AR}	Avalanche Current (note2)	50	A
P _D	Power Dissipation (Ta=25°C)	83	W
T _j	Junction Temperature(Max)	150	°C
T _{stg}	Storage Temperature	-55~+150	
TL	Maximum lead temperature for soldering purpose,1/8" from case for 5 seconds	300	

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
R _{θJC}	Thermal Resistance,Junction to Case	-	1.24	°C/W
R _{θJA}	Thermal Resistance,Junction to Ambient	-	62.5	°C/W

Electrical Characteristics Tc=25°C unless other wise noted						
Symbol	Parameter	Test Condition	Min.	Typ.	Max	Units
Off Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	ID=250 μ A, VGS=0	60	--	--	V
ΔBV _{DSS} / ΔT _J	Breakdown Voltage Temperature Concipient	ID=250 μ A, Reference to 25°C	--	0.06	--	V/°C
IDSS	Zero Gate Voltage Drain Current	Vds=60V, Vgs=0V	--	--	1	μ A
		Vds=48V, Tc=125 °C			10	μ A
IGSSF	Gate-body leakage Current, Forward	Vgs=+25V, Vds=0V	--	--	100	nA
IGSSR	Gate-body leakage Current, Reverse	Vgs=-25V, Vds=0V	--	--	-100	nA
On Characteristics						
V _{GS(th)}	Date Threshold Voltage	Id=250uA, Vds=Vgs	2	--	4	V
R _{DS(on)}	Static Drain-Source On-Resistance	Id=25A, Vgs=10V	--	--	0.018	Ω
Dynamic Characteristics						
Ciss	Input Capacitance	VDS=25V, VGS=0, f=1.0MHz	--	1180	1540	pF
Coss	Output Capacitance		--	440	580	pF
Crss	Reverse Transfer Capacitance		--	65	90	pF
Switching Characteristics						
Td(on)	Turn-On Delay Time	VDD=250V, ID=25A RG=25 Ω (Note 3,4)	--	15	40	nS
Tr	Turn-On Rise Time		--	105	220	nS
Td(off)	Turn-Off Delay Time		--	60	130	nS
Tf	Turn-Off Fall Time		--	65	140	nS
Qg	Total Gate Charge	VDS=400, VGS=10V, ID=25A (Note 3,4)	--	31	41	nC
Qgs	Gate-Source Charge		--	8	--	nC
Qgd	Gate-Drain Charge			13	--	nC
Drain-Source Diode Characteristics and Maximum Ratings						
I _S	Maximun Continuous Drain-Source Diode Forward Current		--	--	50	A
I _{SM}	Maximun Plused Drain-Source DiodeForwad Current		--	--	200	A
V _{SD}	Drain-Source Diode Forward Voltage	Id=25A	--	--	1.5	V
trr	Reverse Recovery Time	I _S =25A, V _{GS} =0V	--	52	--	nS
Qrr	Reverse Recovery Charge	di _F /dt=100A/ μ s (Note3)	--	75	--	μ C
*Notes	1, L=9.3mH, IAS=50A, VDD=50V, RG=25Ω, Starting T _J =25°C 2, Repetitive Rating : Pulse width limited by maximum junction temperature 3, Pulse Test : Pulse Width ≤ 300μs, Duty Cycle ≤ 2% 4, Essentially Independent of Operating Temperature					

Typical Characteristics

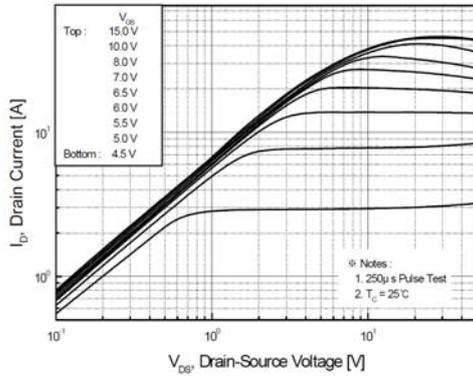


Figure 1. On-Region Characteristics

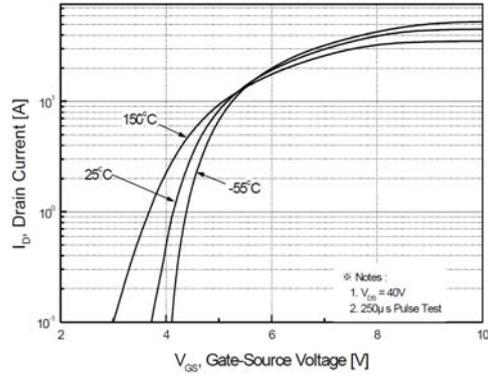


Figure 2. Transfer Characteristics

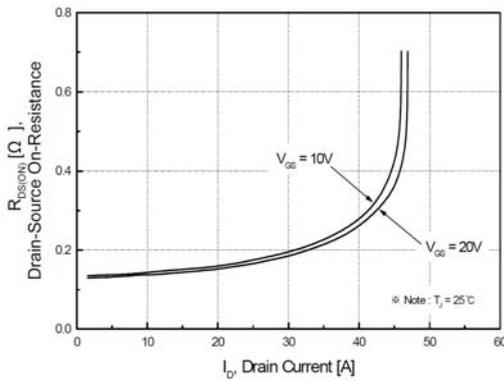


Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage

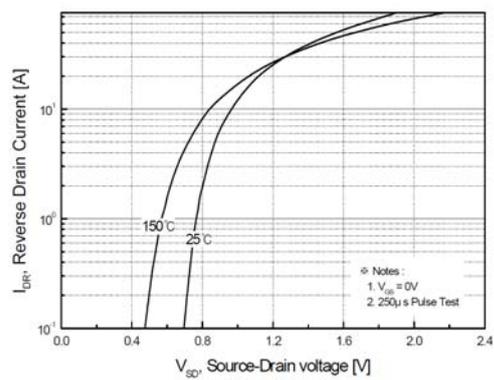


Figure 4. Body Diode Forward Voltage Variation with Source Current and Temperature

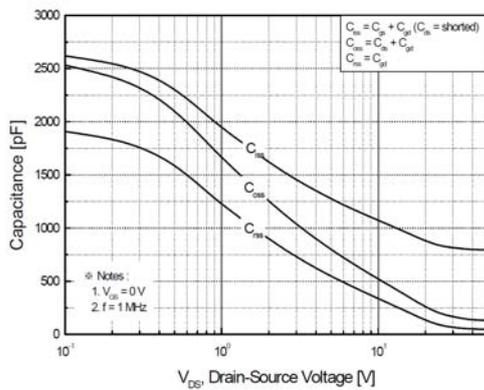


Figure 5. Capacitance Characteristics

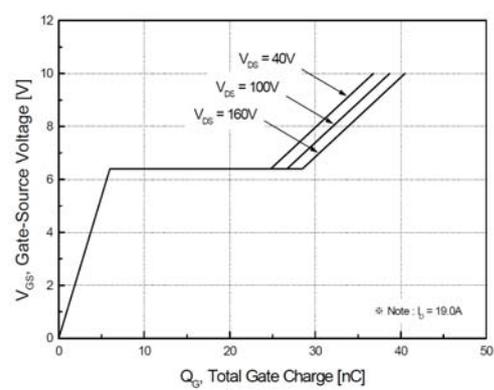


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

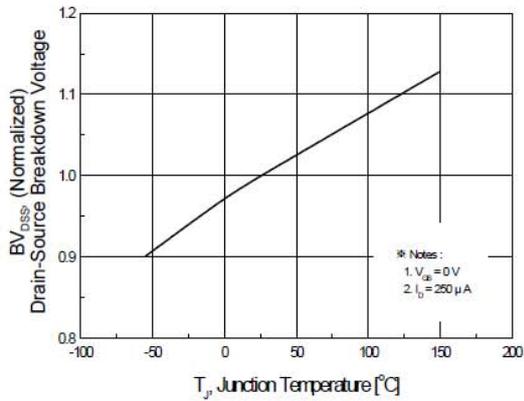


Figure 7. Breakdown Voltage Variation vs Temperature

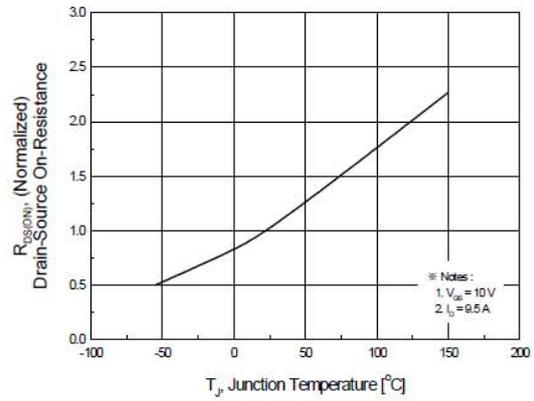


Figure 8. On-Resistance Variation vs Temperature

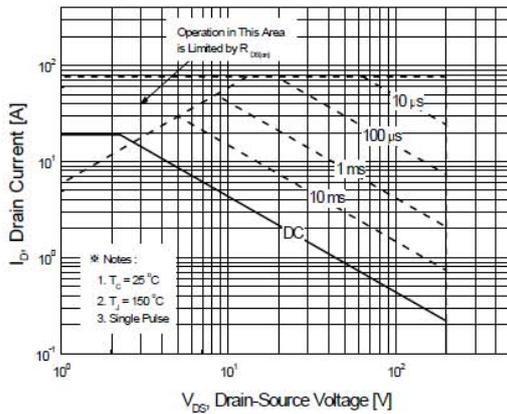


Figure 9. Maximum Safe Operating Area

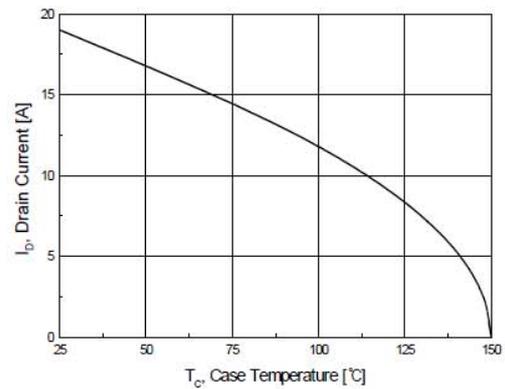


Figure 10. Maximum Drain Current vs Case Temperature

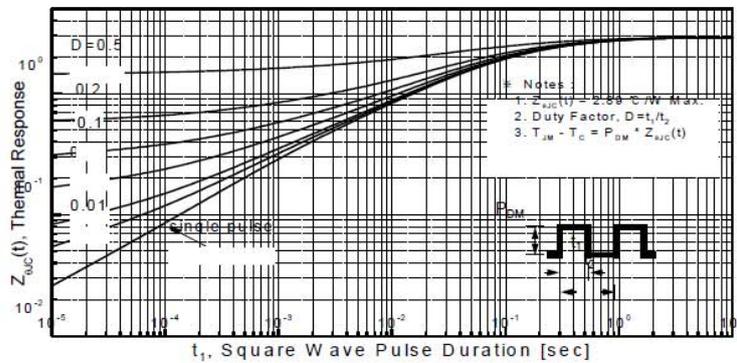
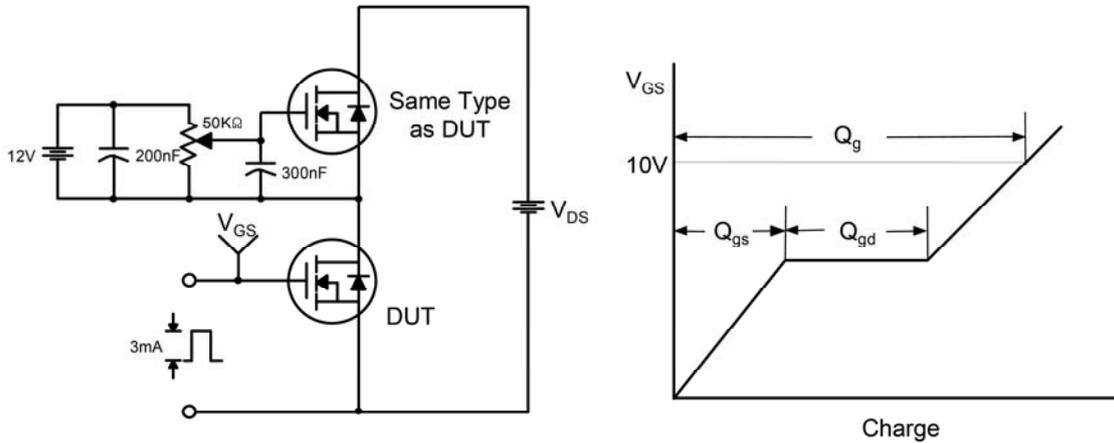
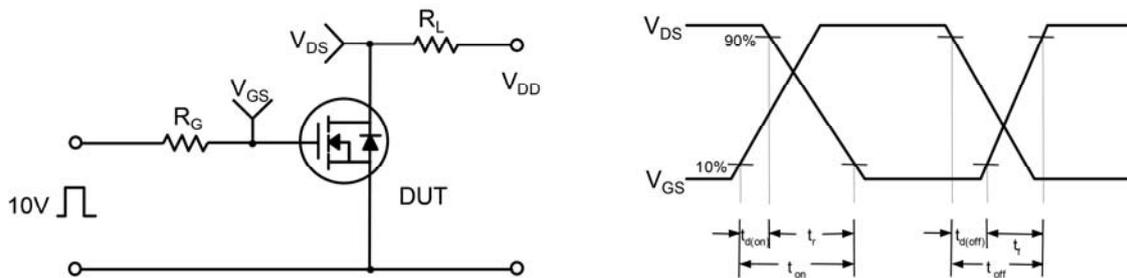


Figure 11. Transient Thermal Response Curve

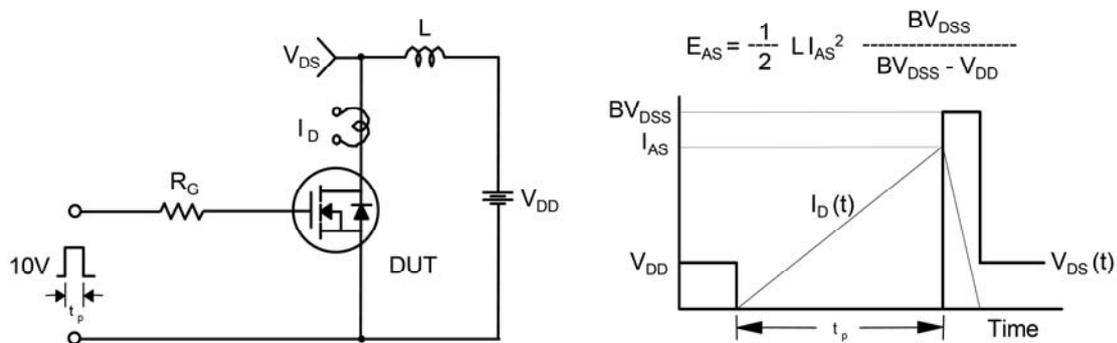
Gate Charge Test Circuit & Waveform



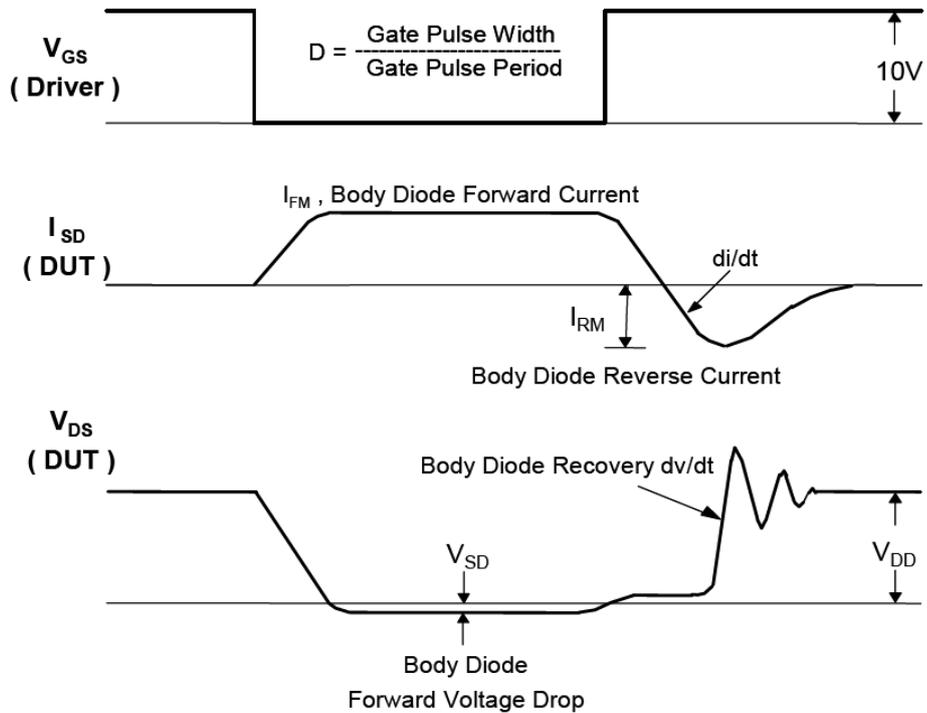
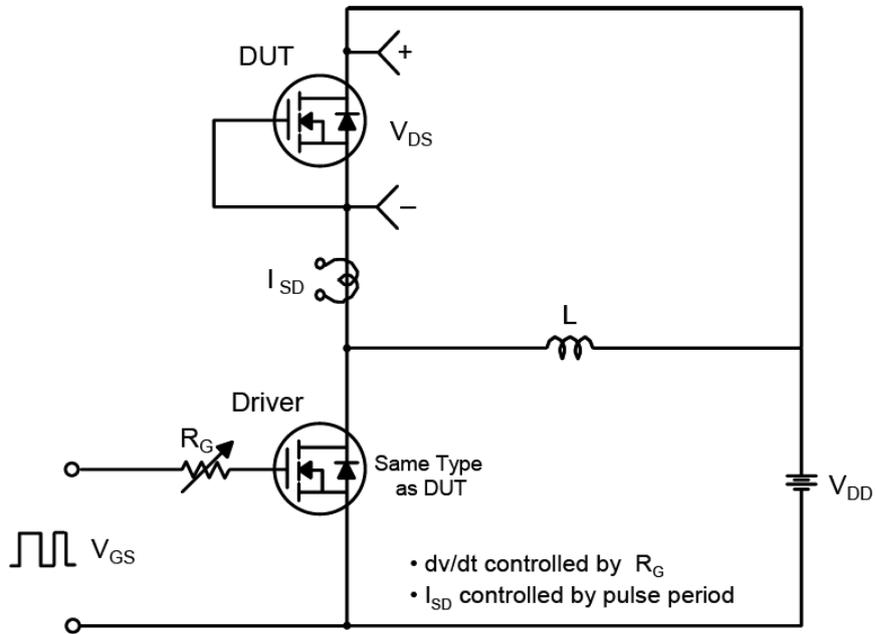
Resistive Switching Test Circuit & Waveforms



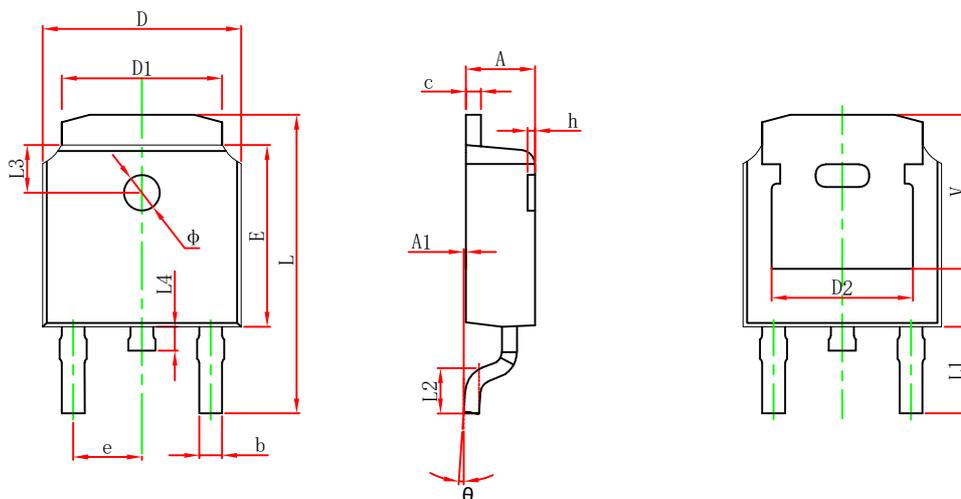
Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveform

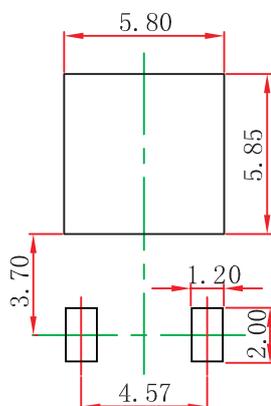


Package Dimension



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	2.200	2.400	0.087	0.094
A1	0.000	0.127	0.000	0.005
b	0.700	0.860	0.025	0.030
c	0.460	0.580	0.018	0.023
D	6.500	6.700	0.256	0.264
D1	5.100	5.460	0.201	0.215
D2	4.830 REF.		0.190 REF.	
E	6.000	6.300	0.236	0.244
e	2.186	2.386	0.086	0.094
L	9.712	10.312	0.382	0.406
L1	2.900 REF.		0.114 REF.	
L2	1.400	1.700	0.055	0.067
L3	1.600 REF.		0.063 REF.	
L4	0.600	1.000	0.024	0.039
Φ	1.100	1.300	0.043	0.051
θ	0°	8°	0°	8°
h	0.000	0.300	0.000	0.012
V	5.250 REF.		0.207 REF.	

TO-252-2L Suggest Pad Layout



NOTE:

1. Controlling dimension: in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.